

DS 51: Graphene (joint session with TT, MA, HL, DY, O)

Time: Friday 11:30–13:15

Location: CHE 89

DS 51.1 Fri 11:30 CHE 89

Plasma-enhanced chemical vapor deposition of graphene on copper substrates — •NICOLAS WÖHRL, OLIVER OCHEDOWSKI, STEVEN GOTTLIEB, and VOLKER BUCK — Universität Duisburg-Essen und CENIDE, 47057 Duisburg, Germany

In this work we present the synthesis of graphene on copper by microwave Plasma-enhanced Chemical Vapor Deposition (PE-CVD) process. The special construction of the plasma source allows the deposition at a wide range of different process parameters giving a fast and inexpensive method to synthesize graphene. Additional advantages of the plasma deposition of graphene are lower substrate temperatures compared with thermal CVD processes. The PE-CVD process uses hydrogen and methane as reaction gases exactly like thermal CVD process does. The gaseous precursors are decomposed in the plasma and the catalytic influence of copper and the minor solubility of carbon in copper lead to the growth of one monolayer of graphene. Plasma parameters are varied to investigate the influence on the graphene properties. Raman spectroscopy and AFM measurements are used as non-destructive tools for the characterization of the synthesized graphene films. Especially Raman spectroscopy is used as an efficient tool to determine the number of graphene layers, the disorder and the defect density. We present a possible way to produce large area of monolayer graphene on a copper based substrate. This technology can help to make graphene available for industrial applications.

DS 51.2 Fri 11:45 CHE 89

Continuous wafer-scale graphene on cubic-SiC(001) — •VICTOR ARISTOV^{1,2}, OLGA MOLODTSOVA², ALEXEI ZAKHAROV³, DMITRY MARCHENKO⁴, JAIME SÁNCHEZ-BARRIGA⁴, ANDREI VARYKHALOV⁴, MARC PORTAIL⁵, MARCIN ZIELINSKI⁶, IGOR SHVETS⁷, and ALEXANDER CHAIKA^{1,7} — ¹ISSP RAS, Chernogolovka, Moscow dist. 142432, Russia — ²HASYLAB at DESY, D-22607 Hamburg, Germany — ³MAX-lab, Lund University, Box 118, 22100 Lund, Sweden — ⁴HZB für Materialien und Energie, D-12489 Berlin, Germany — ⁵CNRS-CRHEA, 06560 Valbonne, France — ⁶NOVASiC, BP267-F73375 Le Bourget du Lac Cedex, France — ⁷CRANN, School of Physics, Trinity College, Dublin 2, Ireland

The atomic and electronic structure of graphene synthesized on commercially available cubic SiC(001)/Si(001) wafers have been studied. LEED, LEEM, PEEM, STM and ARPES data prove the wafer-scale continuity and uniform thickness of the graphene overlayer and reveal that the graphene overlayer consists of only a few monolayers with physical properties of quasi-freestanding graphene: atomic-scale rippling, asymmetric distributions of carbon-carbon bond lengths etc. In addition, graphene overlayer consists of rotated nanometer-sized ribbons with four different lattice orientations connected through the grain boundaries. Thus, this graphene could be adapted for graphene-based electronic technologies and directly patterned using Si-electronic lithographic process. Supported by RFBR grant 14-02-00949, by Marie Curie IIF grant (7th ECFP) and by SPP 1459 of DPG.

DS 51.3 Fri 12:00 CHE 89

Characterization of single and few layer of molybdenum disulfide with spectroscopic imaging ellipsometry — •P. H. THIESEN¹, B. MILLER², C. RÖLING¹, E. PARZINGER², A. W. HOLLEITNER², and U. WURSTBAUER² — ¹Accurion GmbH, Göttingen, Germany — ²Technische Universität München, Walter Schottky Institut, 85748 Garching, Germany

Molybdenum disulfide is a layered transition metal dichalcogenide. From the point of current research, 2D-materials based on MoS₂ are very promising because of the special semiconducting properties. The bulk material has an indirect 1.2 eV electronic bandgap, but single layer MoS₂ has a direct 1.8 eV bandgap. The monolayer can be used in prospective electronic devices like transistors or photo detectors. Like in the initial period of graphene research, the issue is to identify and characterize MoS₂ crystallites of microscopic scale. Imaging ellipsometry is a nondestructive optical method in thin film metrology with a lateral resolution down to 1 micro meter. Imaging ellipsometry has been applied to characterize graphene flakes of few micrometer size [1],[2] and also to identify single layer steps in multilayer graphene/graphite stacks [3]. Delta and Psi Spectra of MoS₂ monolayers as well as maps of the ellipsometric angles will be presented. The

practical aspect of single layer identification will be addressed and the capability of ellipsometric contrast micrographs as a fast tool for single layer identification will be demonstrated. [1] Wurstbauer et al., Appl. Phys. Lett. 97, 231901 (2010) [2] Matkovic et al. J. Appl. Phys. 112, 123523 (2012) [3] Albrektsen et al. J. Appl. Phys. 111, 064305 (2012)

DS 51.4 Fri 12:15 CHE 89

Charge and Spin Transport in Turbostratic Graphene and Graphene Nanoribbons — •NILS RICHTER¹, SEBASTIAN SCHWEIZER², AJIT KUMAR PATRA², YENNY HERNANDEZ³, AKIMITSU NARITA³, XINLIANG FENG³, PETR OSTRIZEK¹, KLAUS MÜLLEN³, and MATHIAS KLÄUI¹ — ¹Institut für Physik, Johannes Gutenberg-Universität Mainz, 55099 Mainz, Germany — ²FB Physik, Universität Konstanz, 78457 Konstanz, Germany — ³Max Planck Institute for Polymer Research, 55128 Mainz, Germany

We present two specially selected allotropes of graphene: Turbostratic graphene (TG) and graphene nanoribbons (GNRs).

TG discs are graphitic microstructures where the twisting of adjacent layers leads to an electronic decoupling. Electrical transport measurements reveal quantum effects such as weak localization and huge charge carrier mobilities (100,000 cm²/Vs) in protected bulk layers [1]. In non-local spin valves we find efficient spin injection over micrometer distances showing large spin diffusion lengths.

Using electromigrated nanojunctions we are able to investigate electrical and spin transport in chemically synthesized GNRs. As they are dispersed in a solvent [2] they can be drop cast on such junctions. With GNRs of different widths and edge geometries we will probe the exciting unconventional properties that have been predicted for these nanostructures [3].

[1] Y. Hernandez et al., arXiv:1301.6087 (under review 2013). [2] A. Narita et al., Nature Chem., in press, DOI: 10.1038/NCHEM.1819. [3] O. Yazyev, Rep. Prog. Phys. 73, 056501 (2010).

DS 51.5 Fri 12:30 CHE 89

Graphene functionalisation with N and O: reversible or permanent modification of the electronic properties? — •PETER BROMMER^{1,2}, ALEX MARSDEN¹, NEIL WILSON¹, GAVIN BELL¹, and DAVID QUIGLEY^{1,2} — ¹Department of Physics, University of Warwick, Coventry, UK — ²Centre for Scientific Computing, University of Warwick, Coventry, UK

For many applications it is essential to modify the electronic properties of graphene in a controlled fashion. This can be achieved via oxygen and nitrogen functionalisation in ultra-high vacuum, leading to a system in which electronic and structural properties can be systematically studied. Low dose oxygen functionalisation (< 5 atomic percent) can be reversed completely by annealing at 200 °C, while nitrogen permanently integrates itself into the material. Here we present insights from DFT calculations on this system, such as the low-energy configurations and simulated transmission electron microscopy (TEM) images, binding energies and effective band structures of the N and O decorated graphene sheets. We directly compare our results with experiments on CVD grown graphene. Angle-resolved photoemission spectroscopy (ARPES) resolves the band structure changes on functionalization, whilst X-ray photoelectron spectroscopy (XPS) provides information about the chemical environment of the defect atoms. Combined, the computational and experimental data can offer insights into the structural changes induced by the functionalisation process and their consequences on the electronic properties of the material.

DS 51.6 Fri 12:45 CHE 89

Revealing the ultrafast process behind the photoreduction of graphene oxide — •DANIEL S. BADALI¹, REGIS Y.N. GENGLER¹, DONGFANG ZHANG¹, KOSTANTINOS DIMOS², KOSTANTINOS SPYROU², DIMITRIOS GOURNIS², and R.J. DWAYNE MILLER¹ — ¹Max Planck Institute for the Structure and Dynamics of Matter, Center for Free Electron Laser Science, Hamburg Center for Ultrafast Imaging, University of Hamburg, Hamburg, Germany — ²Department of Material Science and Engineering, University of Ioannina, Ioannina, Greece

Because of its unique electronic and structural properties, graphene has brought two-dimensional materials to the foreground of material science and nanoelectronic research. As such, reliable methods for producing graphene are in demand and have significant impact on the field

of thin films. In recent years it has been found that irradiating dispersions of graphene oxide in water with ultraviolet light has led to the production of graphene. Although this has been observed in a variety of experimental conditionals, the exact mechanism of the reduction has remained elusive until now. To this end, we have performed careful optical pump-probe measurements which have revealed the chemistry of this process: rather than direct photoreduction, the reduction is mediated by solvated electrons which have been liberated from water molecules by the ultraviolet light. We show that this occurs on an ultrafast timescale in the tens of picoseconds range. Characterization of the final product confirms the removal of oxygen containing groups and the restoration of the honeycomb carbon network of graphene.

DS 51.7 Fri 13:00 CHE 89

Tuning of structural, electronic and optical properties in twisted bilayer MoS₂ — •JENS KUNSTMANN¹, AREND M. VAN DER ZANDE¹, ALEXEY CHERNIKOV¹, DANIEL A. CHENET¹, YUMENG YOU¹, XIAOXIAO ZHANG¹, TIMOTHY C. BERKELBACH¹, PINSHANE Y. HUANG², LEI WANG¹, FAN ZHANG¹, MARK HYBERTSEN^{1,3}, DAVID A. MULLER², DAVID R. REICHMAN¹, TONY F. HEINZ¹, and JAMES C.

HONE¹ — ¹Columbia University, New York, New York, 10027, USA — ²Cornell University, Ithaca, New York, 14853, USA — ³Brookhaven National Laboratory, Upton, New York 11973, USA

With the rise of graphene, atomically thin 2D materials have become the focus of many researchers worldwide. Among them, group 6 transition metal dichalcogenides, such as MoS₂ are new 2D direct gap semiconductors, have been used as field effect transistors and are promising for applications in valleytronics. However, little is understood about the interlayer interactions between 2D materials. We measured dozens of MoS₂ bilayers with well-defined twist angle by stacking single crystal monolayers using ultraclean transfer techniques. We observe that continuous changes in the interlayer twist angle lead to strong, continuous tuning in the indirect optical transitions, the Raman modes, the second harmonic generation, and the reflection spectra. We use electronic structure calculations to show that the tuning in the indirect band transitions arise from an increase of the bilayer separation caused by the van der Waals repulsion of sulfur atoms. These results indicate the possibility of producing new 2D materials with desired properties by tailoring the interlayer alignment in 2D heterostructures.